

Profile likelihood unfolding with large number of bins

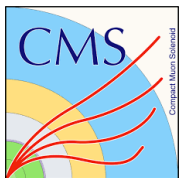
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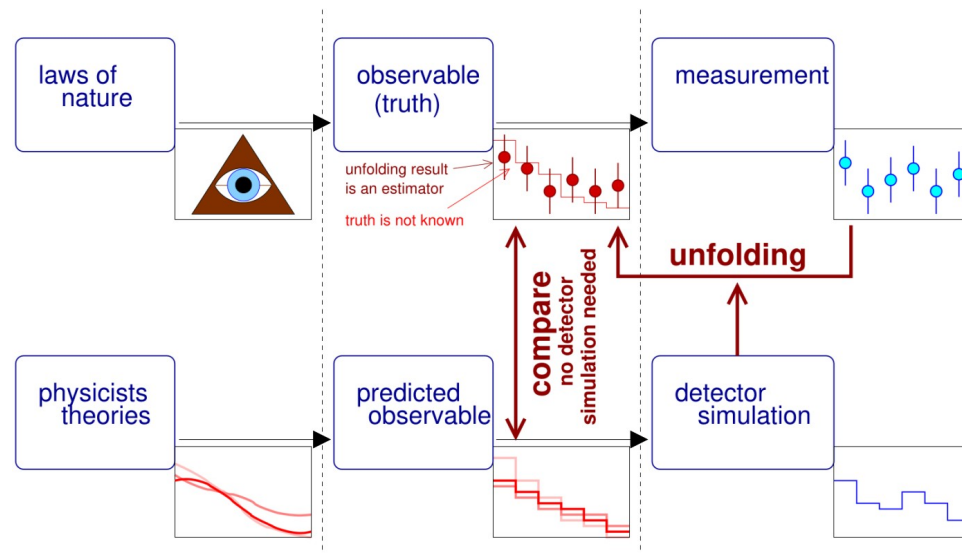


Overview

Binned maximum likelihood unfolding is the genuine solution to Poisson nature of counting experiments

$$\vec{n} | \vec{\lambda} \sim \text{Poisson}(\mathbf{K}\vec{\lambda} + \vec{b})$$

- It gives the smallest unbiased variance



Binned profile likelihood unfolding

- 👍 Background subtraction accounted for directly in likelihood
- 👍 Systematic uncertainties accounted for directly during unfolding as nuisance parameters
- 👍 Profile nuisance parameters during unfolding to make most use of data
- 👍 Simultaneous fit across categories and all bins
- 👎 Expensive numerical minimization

Binned maximum likelihood unfolding

Any template shape fit can be expressed as a many-channel counting experiment, negative log likelihood can be written as

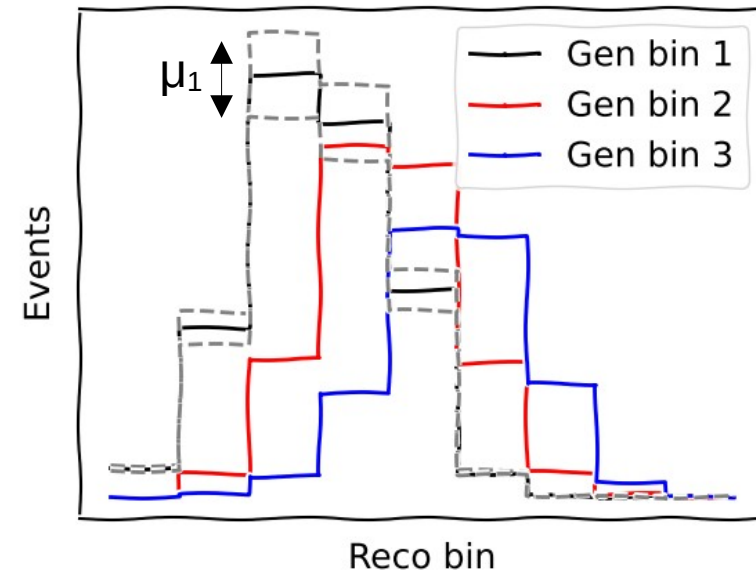
$$L = -\ln \left(\mathcal{L}(\text{data} | \vec{\mu}) \right) = \sum_i^{N^{\text{reco}}} \left(n_i^{\text{obs}} \ln n_i^{\text{exp}}(\vec{\mu}) + n_i^{\text{exp}}(\vec{\mu}) \right)$$

$n_{i,p}^{\text{exp}}$: Yield for each reco bin and process

μ_p : Signal strength modifier for each process

$$n_i^{\text{exp}} = \sum_p^{N^{\text{procs}}} \mu_p n_{i,p}^{\text{exp}}$$

- Each gen bin is represented by a separate process (template), scaled by the μ_p



Binned profile maximum likelihood unfolding

Any template shape fit can be expressed as a many-channel counting experiment, negative log likelihood can be written as

$$L = -\ln \left(\mathcal{L}(\text{data} | \vec{\mu}, \vec{\Theta}) \right) = \sum_i^{N_{\text{reco}}} \left(n_i^{\text{obs}} \ln n_i^{\text{exp}}(\vec{\mu}, \vec{\Theta}) + n_i^{\text{exp}}(\vec{\mu}, \vec{\Theta}) \right) + \sum_k^{N_{\text{syst}}} \frac{1}{2} (\Theta_k - \Theta_k^0)^2$$

$n_{i,p}^{\text{exp}}$: Yield for each reco bin and process

μ_p : Signal strength modifier for each process

$$n_i^{\text{exp}} = \sum_p^{N_{\text{procs}}} \mu_p n_{i,p}^{\text{exp}} \prod_k^{N_{\text{syst}}} \kappa_{i,p,k}^{\Theta_k}$$

- Each gen bin is represented by a separate process (template), scaled by the μ_p

Θ_k : Nuisance parameter constrained to unit Gaussian for each systematic uncertainty

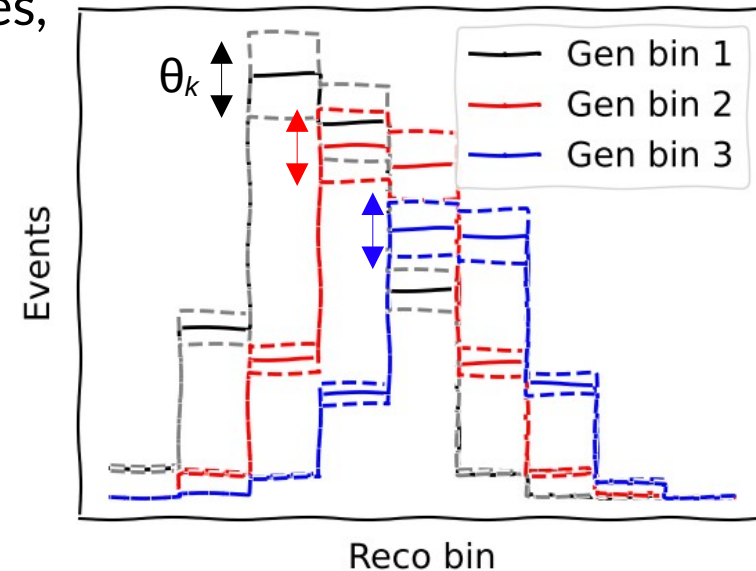
κ : size of systematic, 3D tensor of reco bins, processes, and nuisance parameters (log normal variations)

- The templates are scaled correlated for each systematic uncertainty

$$\kappa_{i,p,k} = 1 + \frac{\sigma_{i,p,k}^{\text{exp}}}{n_{i,p}^{\text{exp}}}$$

- #Histograms \sim #gen bins \cdot #systematics

- Potentially 10's of thousands of histograms



Binned profile maximum likelihood unfolding

Uncertainties/ covariances can be inferred from likelihood function

$$L = -\ln \left(\mathcal{L}(\text{data} | \vec{\mu}, \vec{\Theta}) \right) = \sum_i^{N_{\text{reco}}} \left(n_i^{\text{obs}} \ln n_i^{\text{exp}}(\vec{\mu}, \vec{\Theta}) + n_i^{\text{exp}}(\vec{\mu}, \vec{\Theta}) \right) + \sum_k^{N_{\text{syst}}} \frac{1}{2} (\Theta_k - \Theta_k^0)^2$$

- Exact: Likelihood scan – computationally expensive/slow
- In Gaussian limit: Covariance = Inverse Hessian matrix (second derivative)

In summary

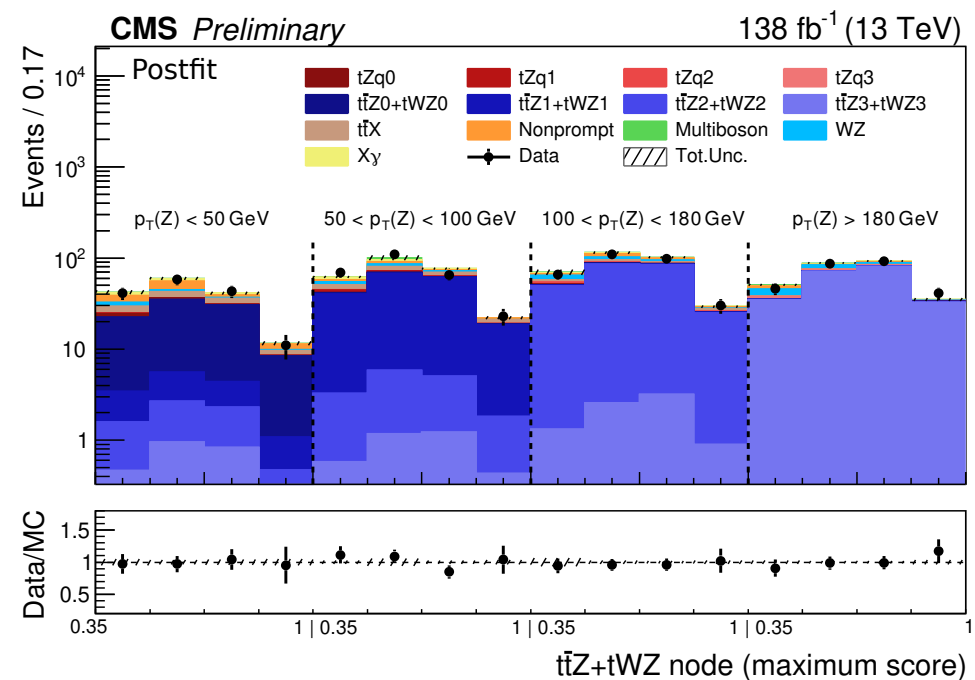
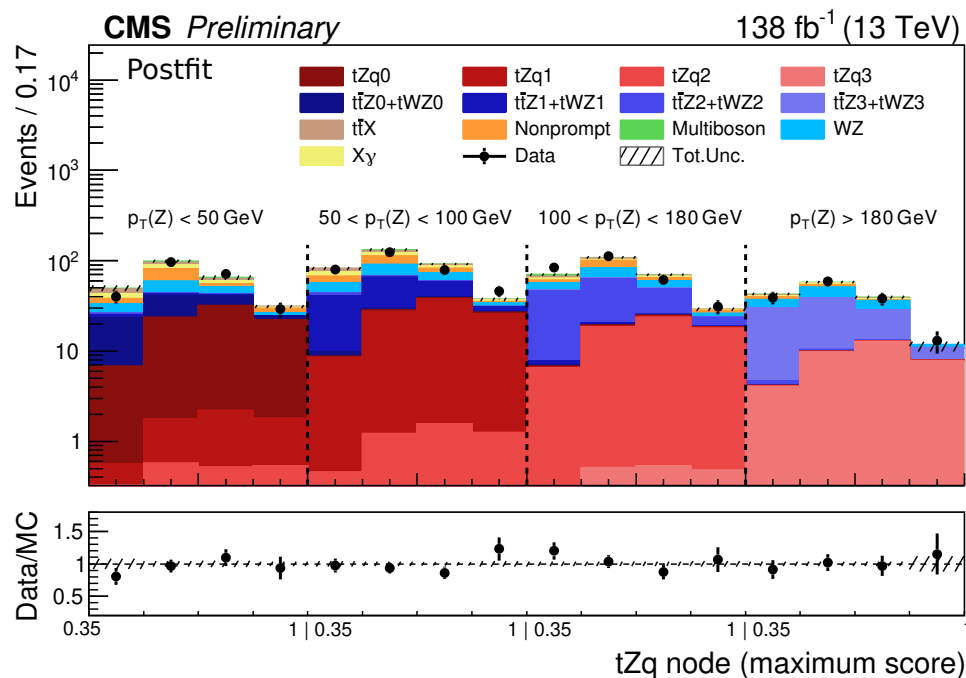
- Challenging minimization problem
- Convergence to global minimum required
- Uncertainties/ covariances need to be computed accurately
- Time/memory of minimization must be kept under control

$$\mathbf{H}_f = \begin{bmatrix} \frac{\partial^2 f}{\partial x_1^2} & \frac{\partial^2 f}{\partial x_1 \partial x_2} & \cdots & \frac{\partial^2 f}{\partial x_1 \partial x_n} \\ \frac{\partial^2 f}{\partial x_2 \partial x_1} & \frac{\partial^2 f}{\partial x_2^2} & \cdots & \frac{\partial^2 f}{\partial x_2 \partial x_n} \\ \vdots & \vdots & \ddots & \vdots \\ \frac{\partial^2 f}{\partial x_n \partial x_1} & \frac{\partial^2 f}{\partial x_n \partial x_2} & \cdots & \frac{\partial^2 f}{\partial x_n^2} \end{bmatrix}$$

Example 1: multi process unfolding in CMS

tZq, ttZ, and tWZ are mutual backgrounds

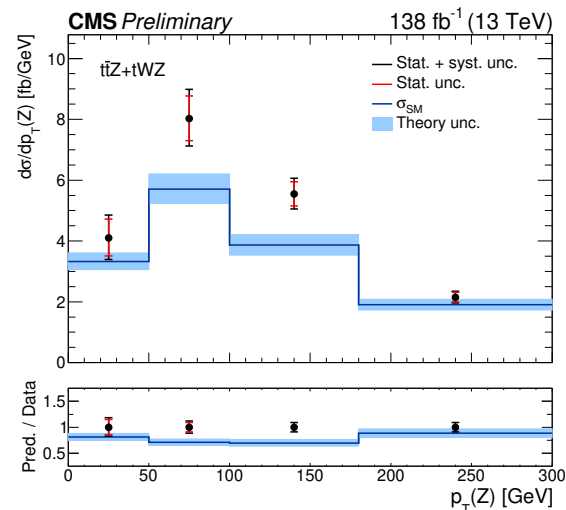
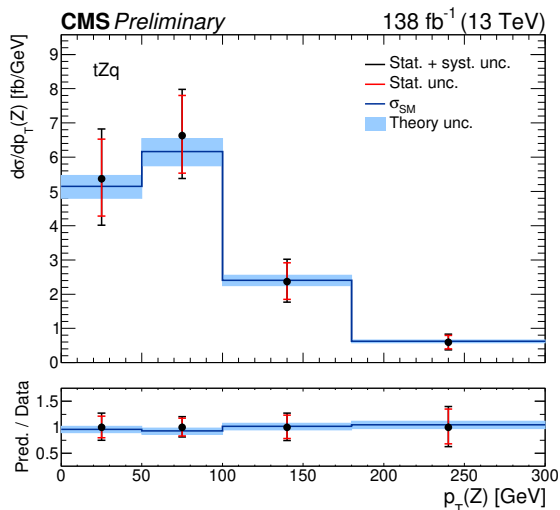
- Simultaneously unfold differential cross sections
- Combined fit of tZq and ttZ enriched selection
- Fit reco variable and event classifier to separate gen bins and processes



Example 1: multi process unfolding in CMS

Obtain unfolded cross sections together with full covariance matrix

- Allow consistent re interpretation e.g. in EFT (operators effect both processes)



Specifications: 144 reco bins, 8 gen bins 13 processes in total, ~400 systematics

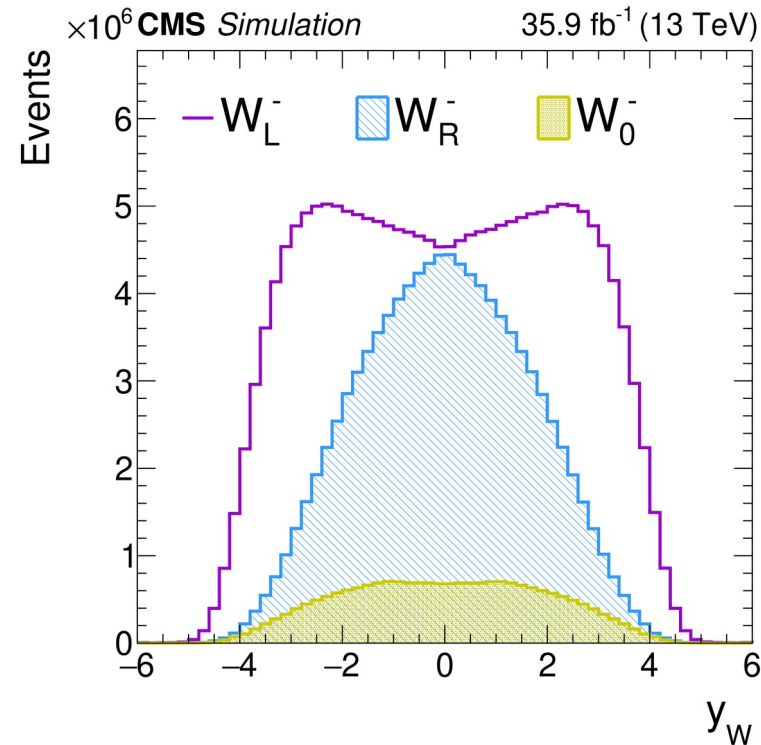
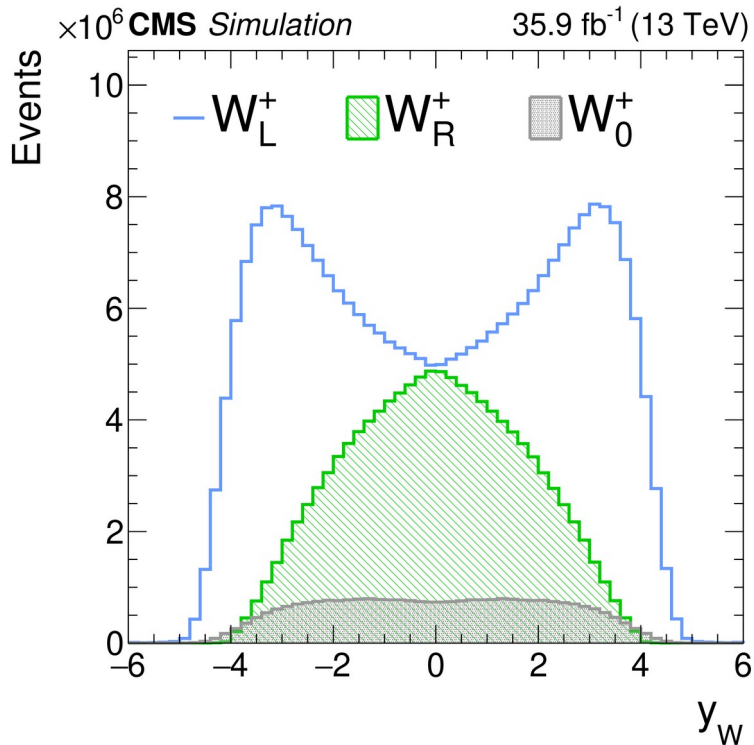
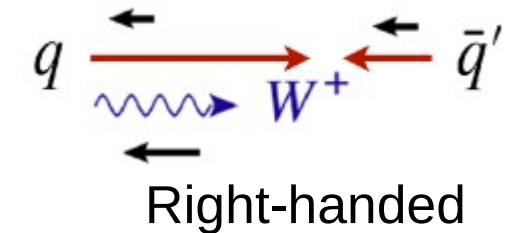
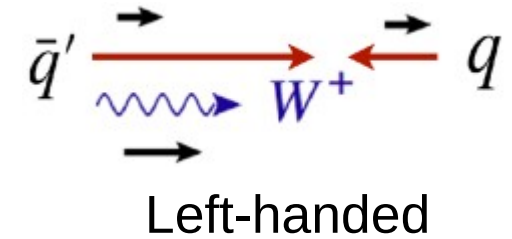
- O(1,000) histograms
- Computationally “easy” with today's hardware
- Done on traditional CMS way with Combine (roofit via minuit)

Example 2: W helicity in CMS

At LO at LHC, W produced via $q\bar{q}$

Due to pure left handed coupling, W helicity determined by its direction relative to incoming quark

- W helicity contains information about PDFs



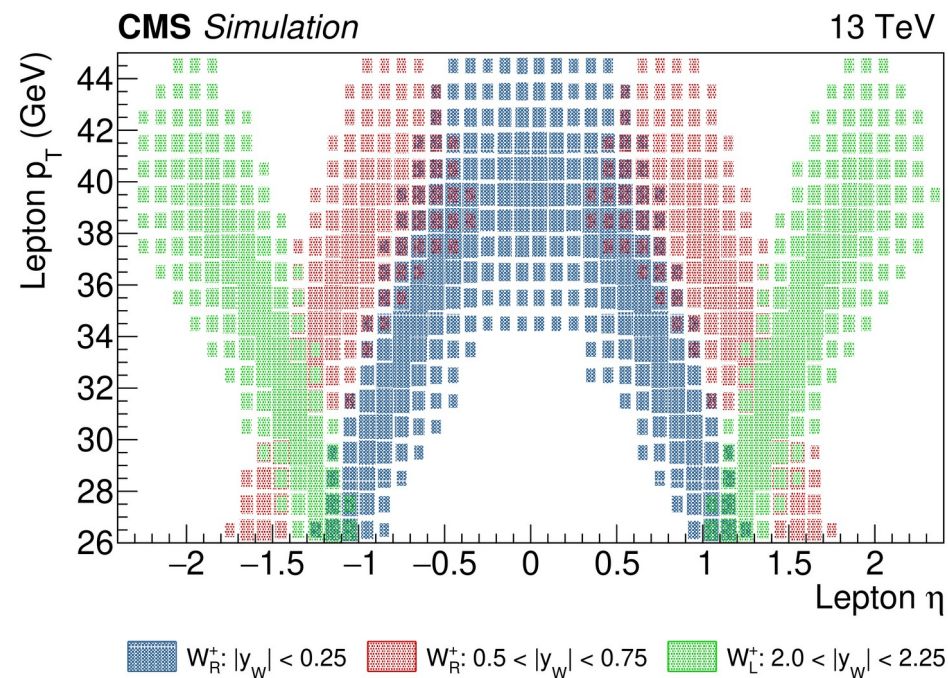
Example 2: W helicity in CMS

Decay (anti) lepton prefers to travel (alongside) against direction of W spin

- Polarization states can be extracted from charged lepton $|\eta|$ - p_T distribution
- Avoid dependence on less precise MET

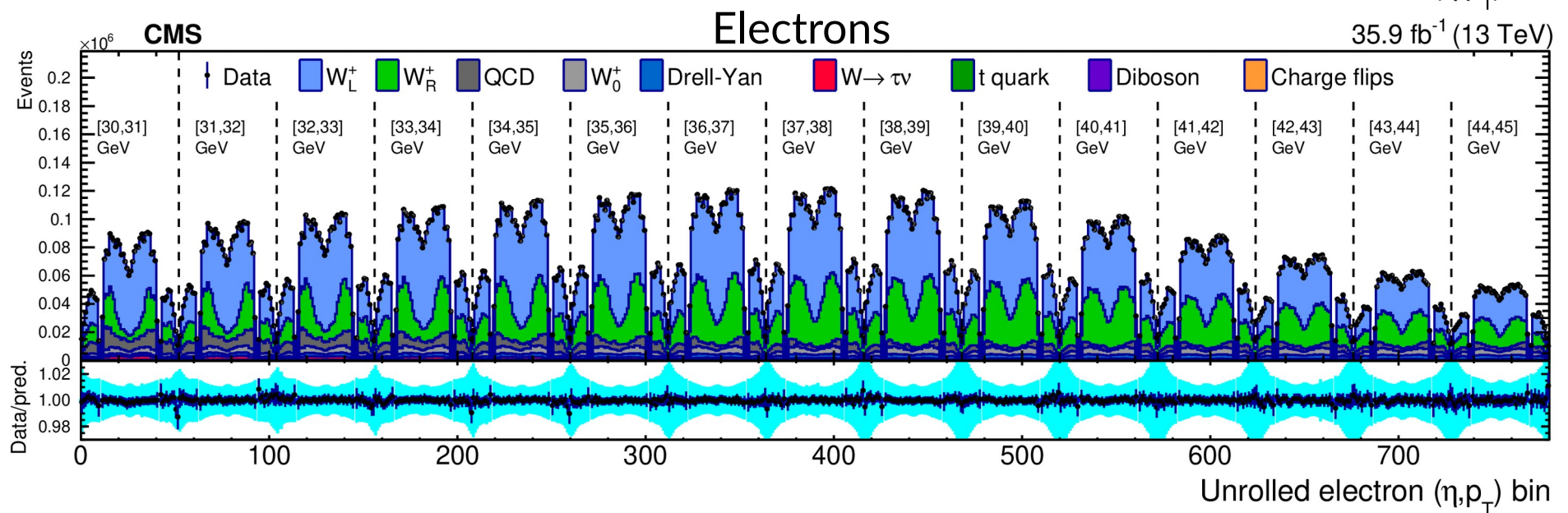
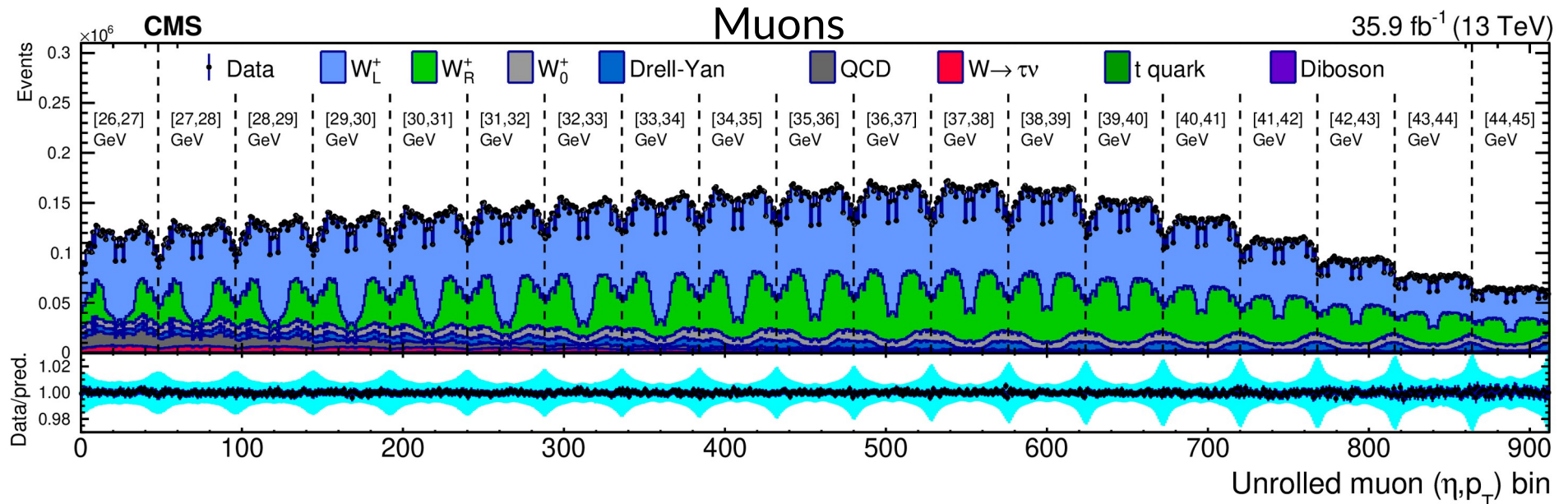
Measure transverse polarization states for W^+ and W^- in bins of boson rapidity

- Longitudinal component fixed to theory prediction with inflated uncertainty
- Separate signal template for each gen bin



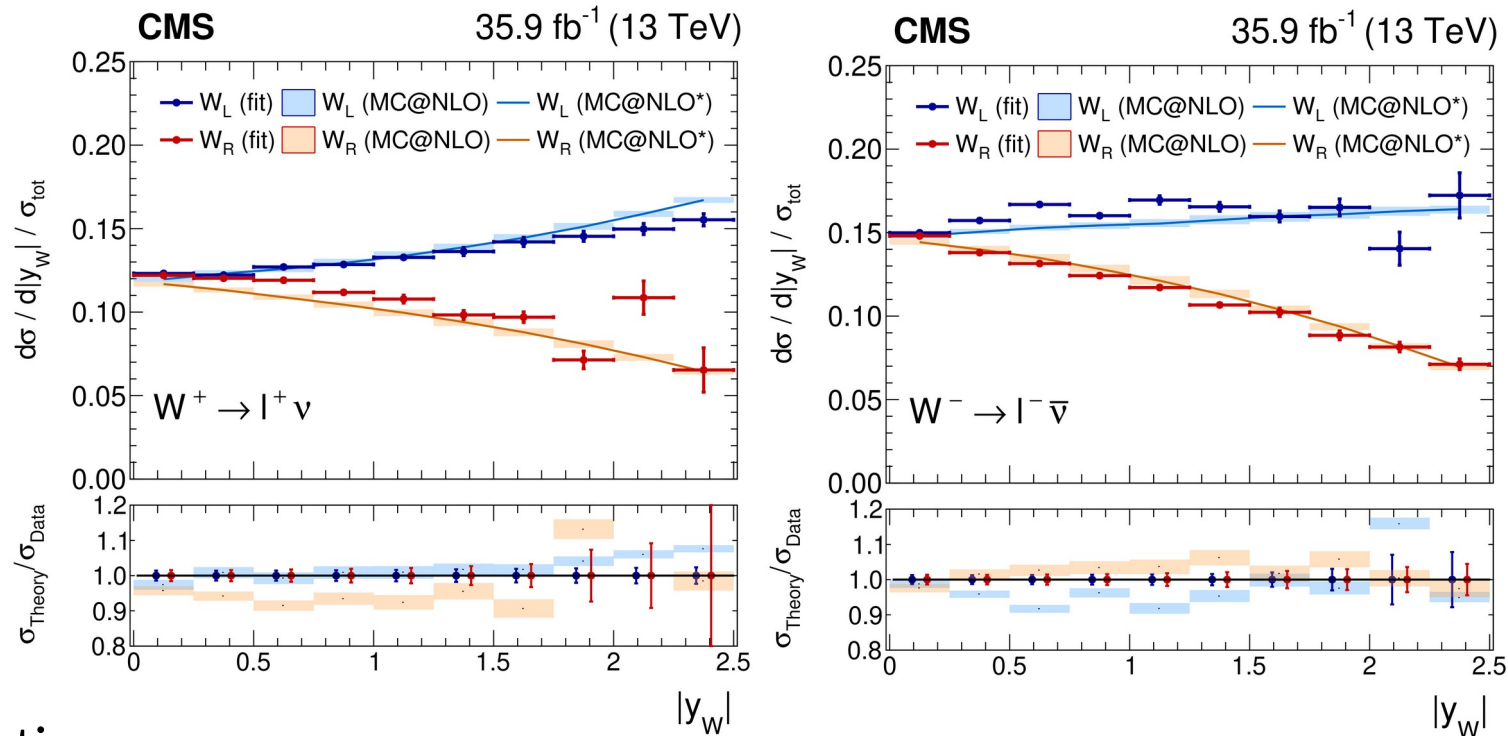
Example 2: W helicity in CMS

Reco distributions for one charge



Example 2: W helicity in CMS

Unfolded differential cross sections with full covariance matrix



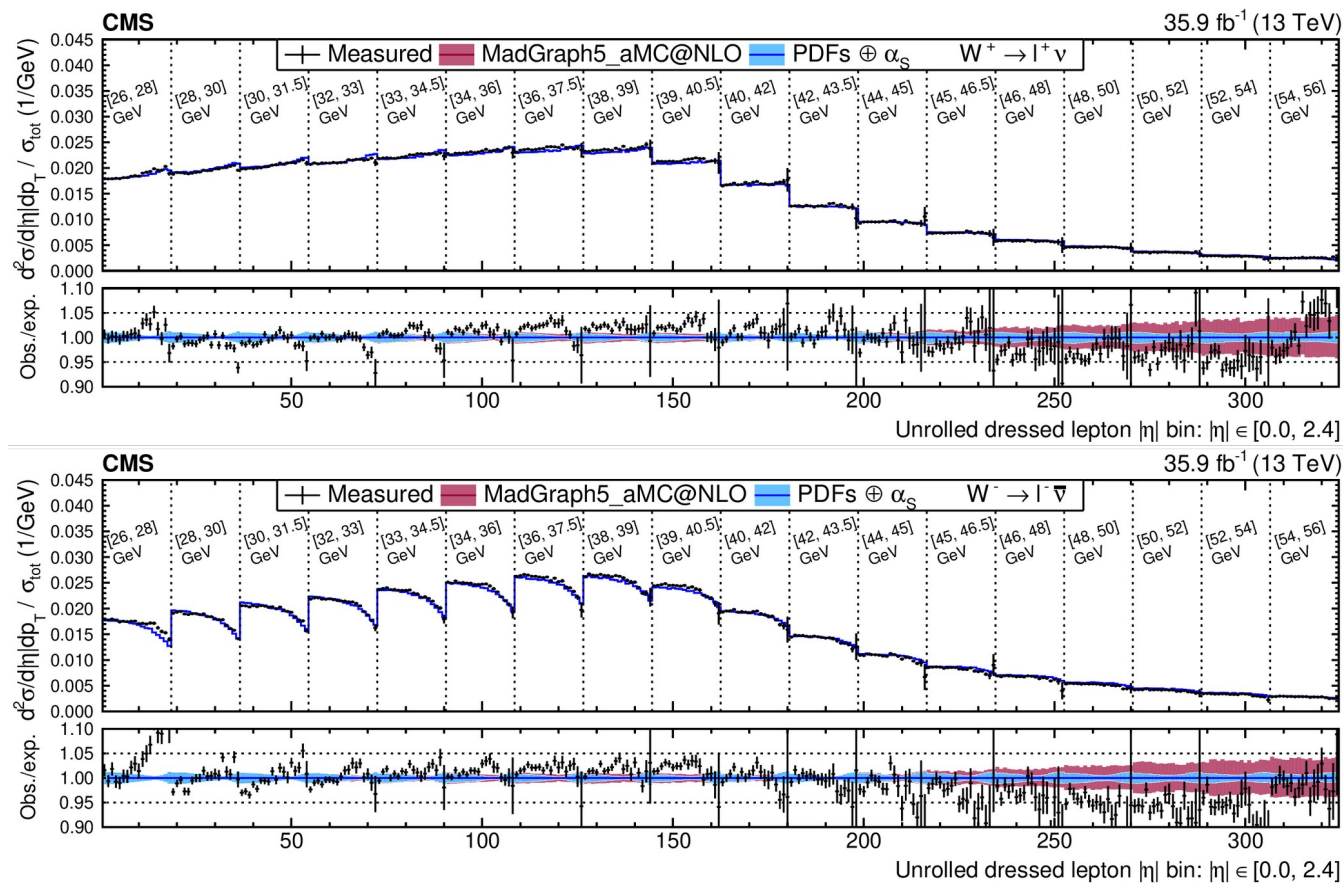
Specifications:

- 3320 reco bins, 40 gen bins, 78 processes in total
- 1354 systematic uncertainties
 - Theory (PDFs, QCD scale, ...) Experiment (efficiencies, lepton energy/momentum scale, backgrounds, ...)
- O(100,000) histograms
- It's "challenging"

Example 2: W helicity in CMS

Also measured:

- Double differential cross section in $|\eta|$ and p_T for W^+ and W^- simultaneously
- $2 \times 18 \times 18 = 648$ gen bins
- 2448 reco bins
- 1051 nuisance parameters



The tool: minimization with tensorflow

Roofit via minuit insufficient

- Limited stability and efficiency (e.g. can not be parallelized)

Tensorflow library with automatic gradient computation via back propagation for minimization:

- Second derivative, trust region based minimizer to reliably find global minimum [\[arXiv:1506.07222\]](#)
- Fast, numerically accurate, stable
- Parallelized vector processing units and/or multiple threads
- Sparse tensor implementation to minimize memory consumption (if response matrix is close-to-diagonal, e.g. leptonic observables)
- See also [\[talk at PyHEP 2020 from J. Bendavid\]](#)

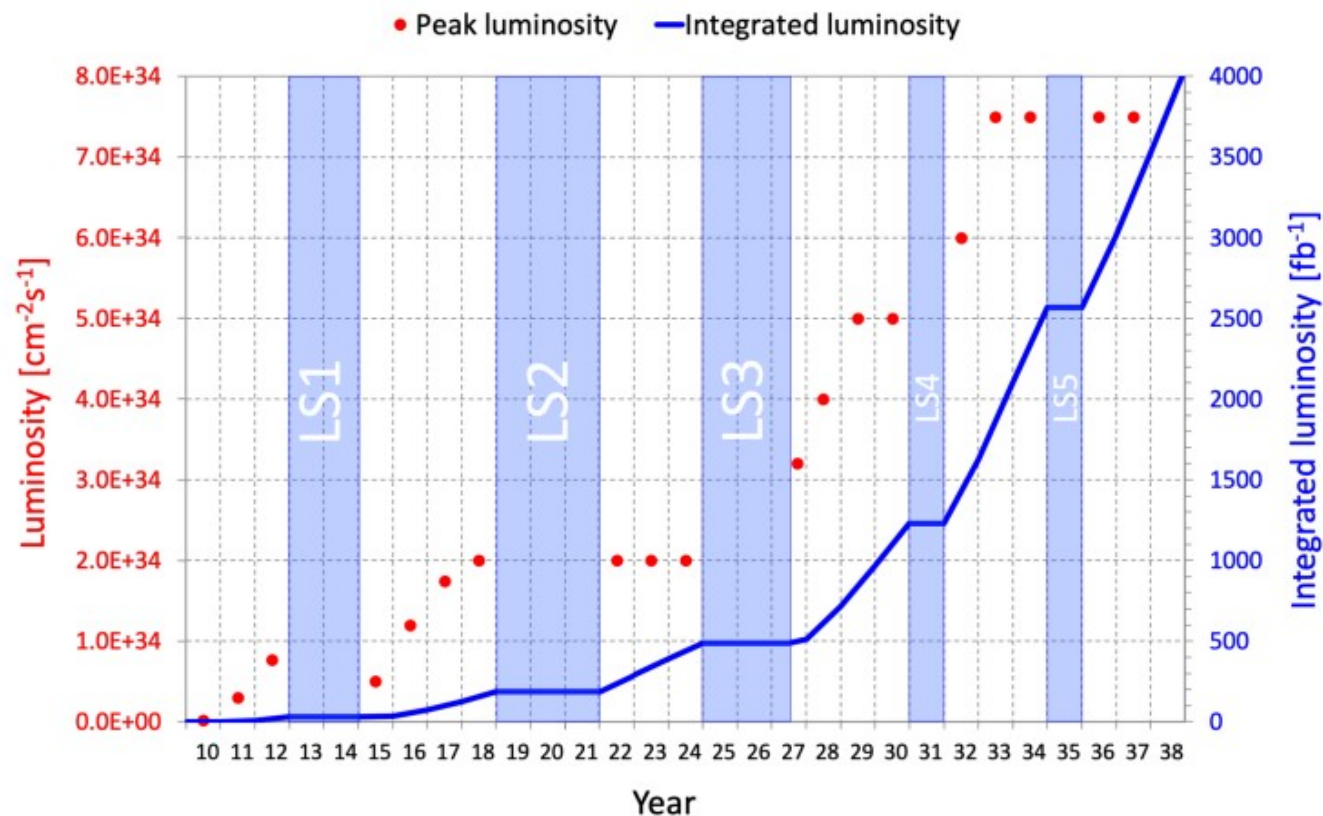
Future upgrade to newer tools foreseen, such as tensorflow 2, JAX, ...

- More efficient computation of hessian matrix

The future of profile likelihood unfolding

Previous analysis was “only” on 2016 data, a small fraction of current data and what will come with Run 3/ HL LHC

- More data will allow finer & more gen and reco bins
- More processes can be measured simultaneously
- Combination of data taking periods and improved precision will require more nuisance parameters

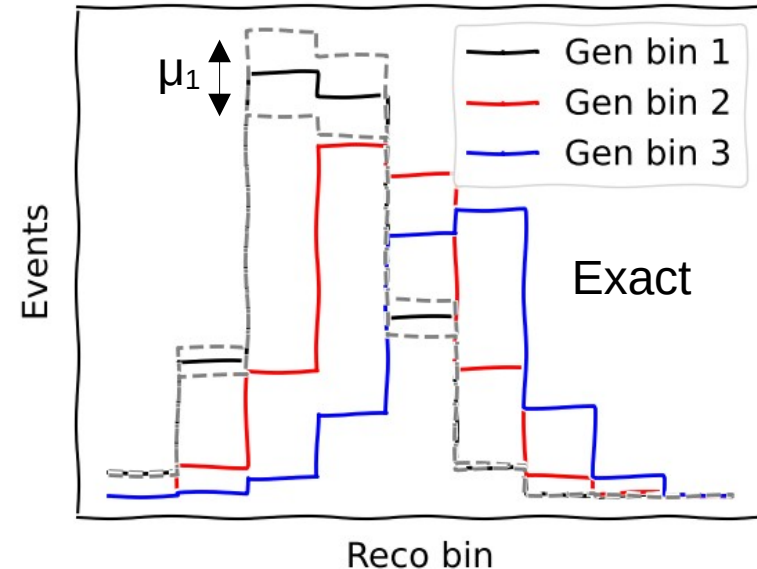


Linearized profile likelihood unfolding

3D tensor will grow to an unmanageable size

- Memory and computation
- #Histograms \sim #gen bins \cdot #systematics

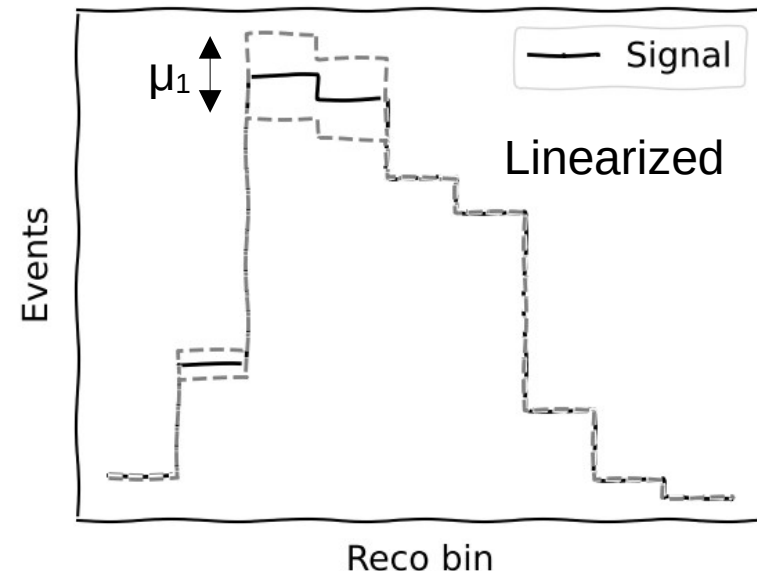
$$n_i^{\text{exp}} = \sum_p^{N_{\text{procs}}} \mu_p n_{i,p}^{\text{exp}} \prod_k^{N_{\text{syst}}} \kappa_{i,p,k}^{\Theta_k}$$



Linearize the dependence of the signal (sum of gen bins) on nuisance parameters

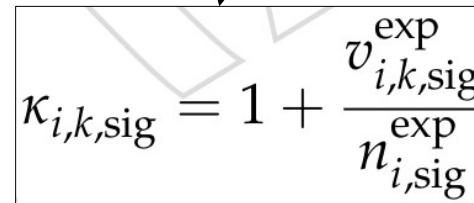
$$n_i^{\text{exp}} = \sum_p^{N_{\text{bkg}}} n_{i,p}^{\text{exp}} \prod_k^{N_{\text{syst}}} \kappa_{i,p,k}^{\Theta_k} + n_{i,\text{sig}}^{\text{exp}} \prod_k^{N_{\text{syst}}} \kappa_{i,k,\text{sig}}^{\Theta_k} \prod_l^{N_{\text{gen}}} \kappa_{i,l,\text{sig}}^{\mu_l}$$

- Treating signal strength multiplier similar to nuisance parameters
- Signal tensor reduced to 2D
- #Histograms \sim #gen bins + #systematics



Linearized profile likelihood unfolding

$$n_i^{\text{exp}} = \sum_p^{N^{\text{bkg}}} n_{i,p}^{\text{exp}} \prod_k^{N^{\text{syst}}} \kappa_{i,p,k}^{\ominus_k} + n_{i,\text{sig}}^{\text{exp}} \prod_k^{N^{\text{syst}}} \kappa_{i,k,\text{sig}}^{\ominus_k} \prod_l^{N^{\text{gen}}} \kappa_{i,l,\text{sig}}^{\mu_l}$$

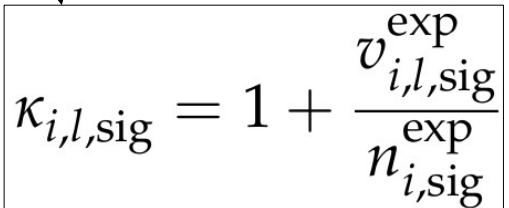

$$\kappa_{i,k,\text{sig}} = 1 + \frac{v_{i,k,\text{sig}}^{\text{exp}}}{n_{i,\text{sig}}^{\text{exp}}}$$

Size of systematic effect $v_{i,k,\text{sig}}^{\text{exp}}$ does not directly depend on individual gen bins anymore

- This assumption could potentially lead to a bias
- But signal strength modifier are unconstrained, starting value can be chosen freely
- Iterative procedure applied to mitigate bias
 - 1) Initial fit
 - 2) Re compute histograms with reweighting gen bin contribution via postfit signal strength modifiers
 - 3) Repeat fit

Linearized profile likelihood unfolding

$$n_i^{\text{exp}} = \sum_p^{N^{\text{bkg}}} n_{i,p}^{\text{exp}} \prod_k^{N^{\text{syst}}} \kappa_{i,p,k}^{\ominus_k} + n_{i,\text{sig}}^{\text{exp}} \prod_k^{N^{\text{syst}}} \kappa_{i,k,\text{sig}}^{\ominus_k} \prod_l^{N^{\text{gen}}} \kappa_{i,l,\text{sig}}^{\mu_l}$$


$$\kappa_{i,l,\text{sig}} = 1 + \frac{v_{i,l,\text{sig}}^{\text{exp}}}{n_{i,\text{sig}}^{\text{exp}}}$$

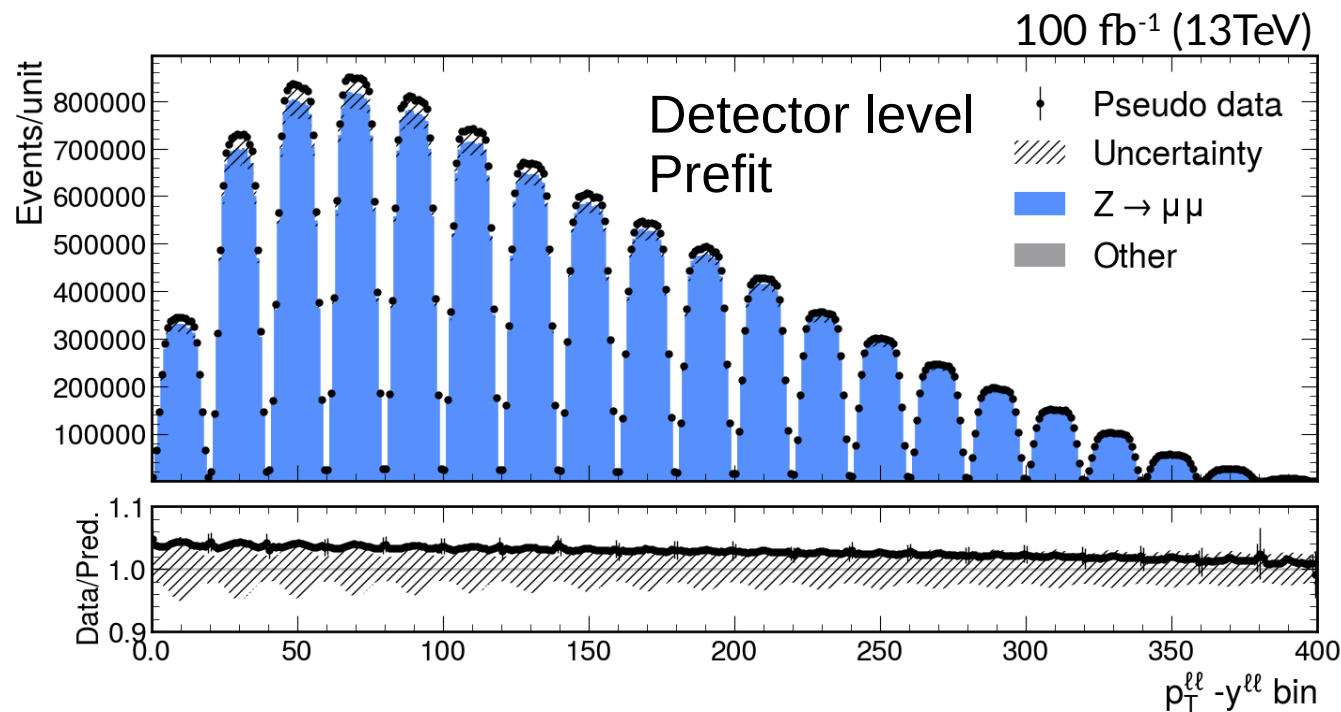
Size of gen bin variation $v_{i,l,\text{sig}}^{\text{exp}}$ is in principle arbitrary

- Small dependency observed – mainly for convergence of iterative procedure

Linearized profile likelihood unfolding

Validation: benchmark linearized likelihood unfolding vs. exact likelihood unfolding

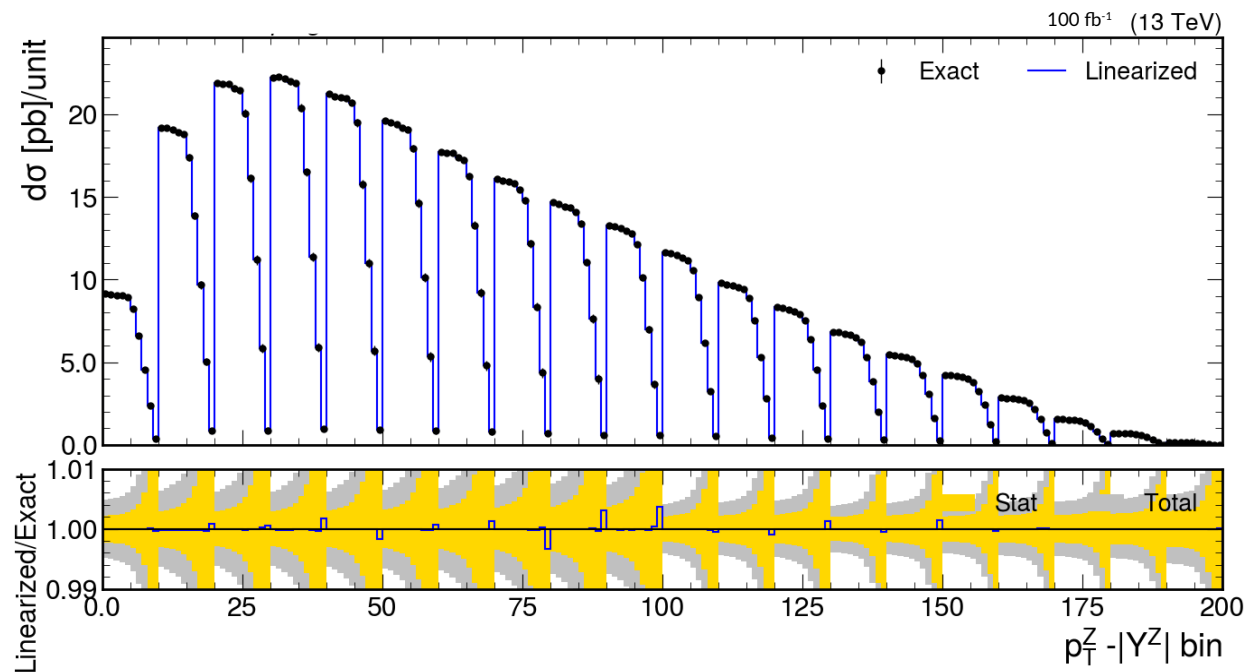
- Real world example: use MiNNLO MC with realistic detector simulation and unfold Z boson dilepton p_T , $|Y|$
 - 200 gen bins
 - 400 reco bins
 - 41 Explicit nuisance parameters (PDFs + α_s) + implicit MC stat. uncertainties
- Inject pseudo data by reweighting to HERAPDF2.0 PDF set (nominal is PDF4LHC21)
 - Do central values and uncertainties agree?



Linearized profile likelihood unfolding

Extracted differential cross section from initial fit

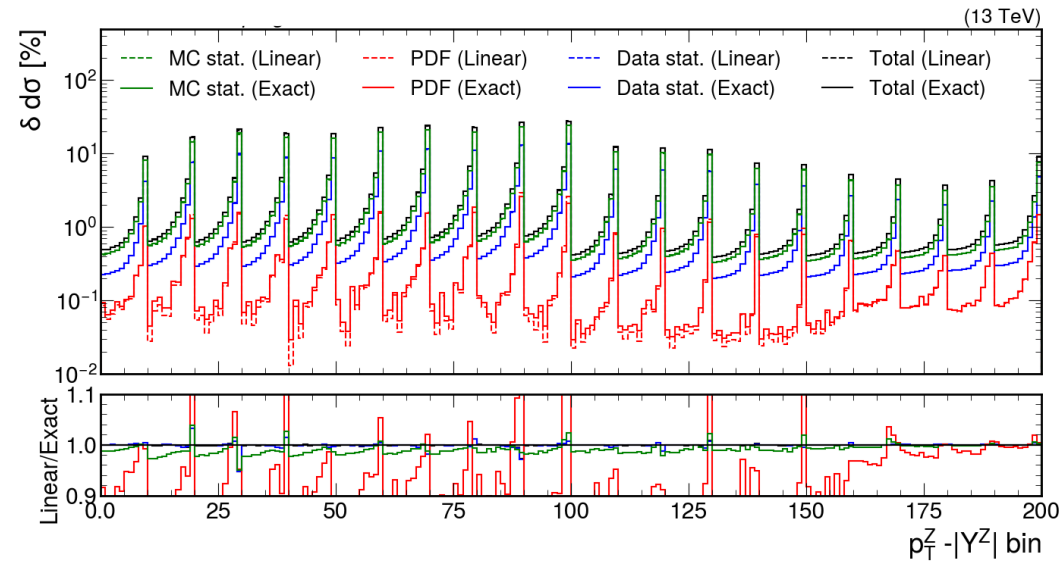
- Almost perfect agreement in central values between exact and linearized unfolding
- Deviations much smaller than stat. uncertainty



Linearized profile likelihood unfolding

Relative uncertainties from initial fit

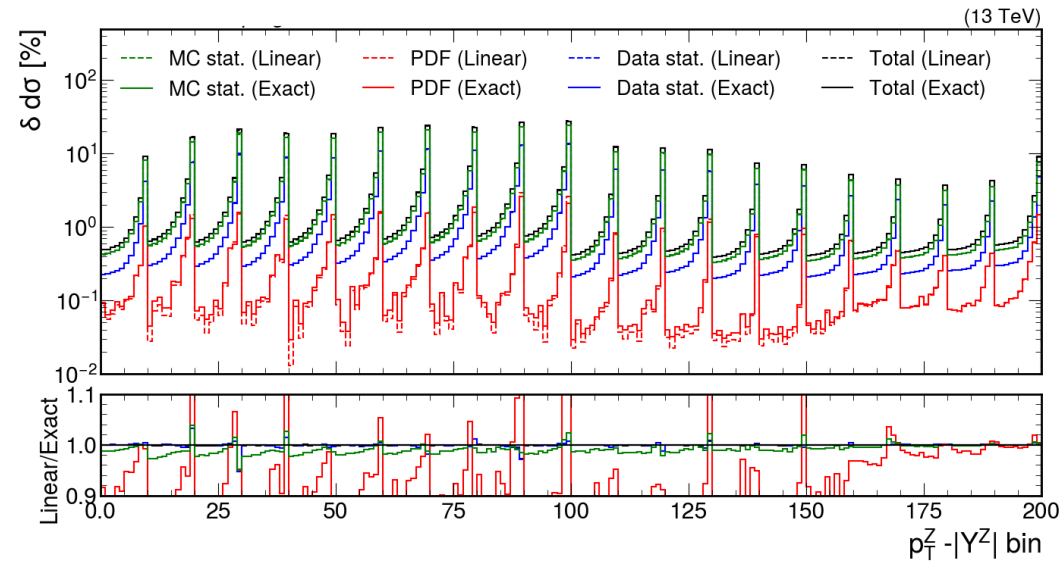
- Good agreement in total and data stat. uncertainty
- Larger relative disagreement for some individual sources of uncertainties e.g. MC stat. (green) and PDF (red)



Linearized profile likelihood unfolding

Relative uncertainties

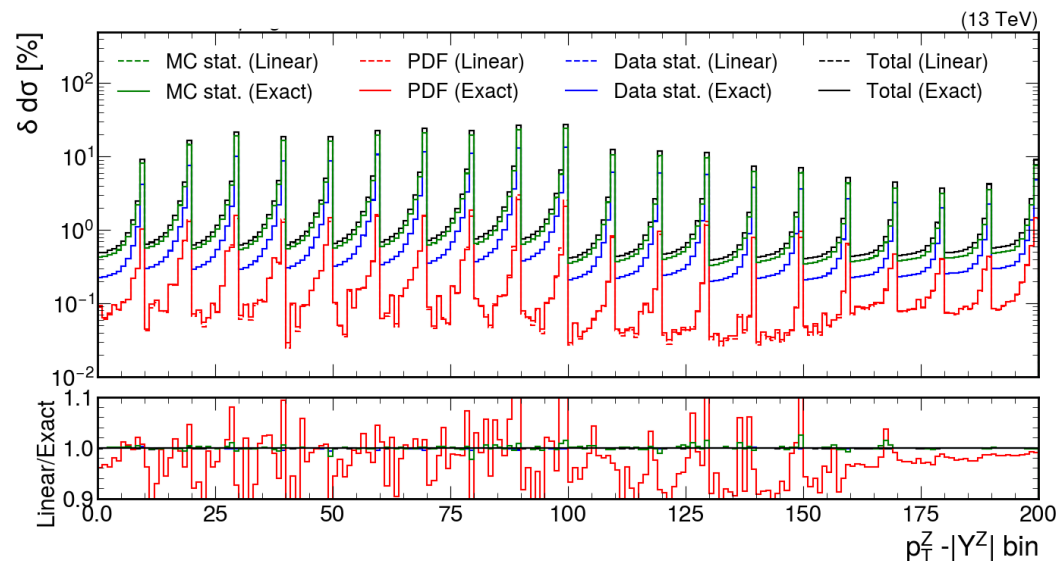
- Good agreement in total and data stat. uncertainty
- Larger relative disagreement for some individual sources of uncertainties e.g. MC stat. (green) and PDF (red)



Agreement improves through iterative procedure of linearized unfolding

- Re compute histograms with reweighting gen bin contribution via postfit signal strength modifiers – and repeat fit
- Size of gen bin variation $v_{i,l,\text{sig}}^{\text{exp}}$ chosen as 1% of gen bin contribution
 - Better choice possible, e.g. based on uncertainty
 - Studies ongoing

↓ 1 iteration



Summary

Unfolded distributions provide input for global PDF/EFT/... fits

Binned profile likelihood unfolding is established as a reliable method

- Problem requires expensive numerical minimization

Modern libraries with automatic differentiation via back propagation allow robust and fast minimization

- Unfolding with up to 1000 gen bins well possible

However, complexity may grow soon to unmanageable level

- Linearization procedures can provide remedy
- Validation shows agreement with exact likelihood unfolding can be restored via iterative procedure (1 iteration sufficient in realistic toy study)

Backup